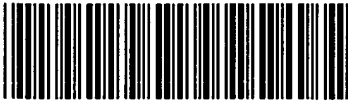


**Search Notes**

Application/Control No.

10/801,706

Examiner

Evan Dzierzynski

Applicant(s)/Patent under  
Reexamination

PAN, WUN-FANG

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
439	680	11/1/2005	EPD
	699.2	11/1/2005	EPD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Word search in EAST, see attachment	11/1/2005	EPD